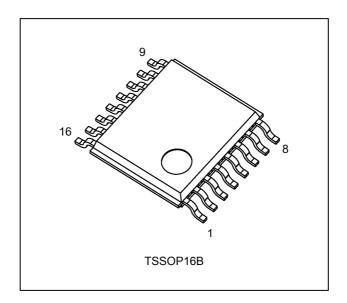
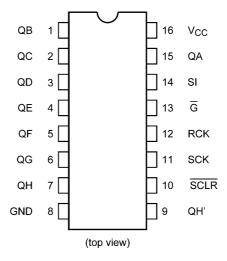


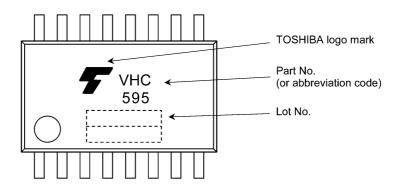
4. Packaging



5. Pin Assignment

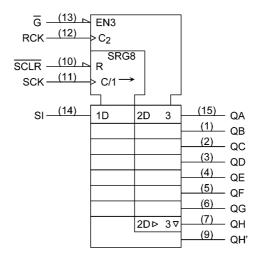


6. Marking





7. IEC Logic Symbol



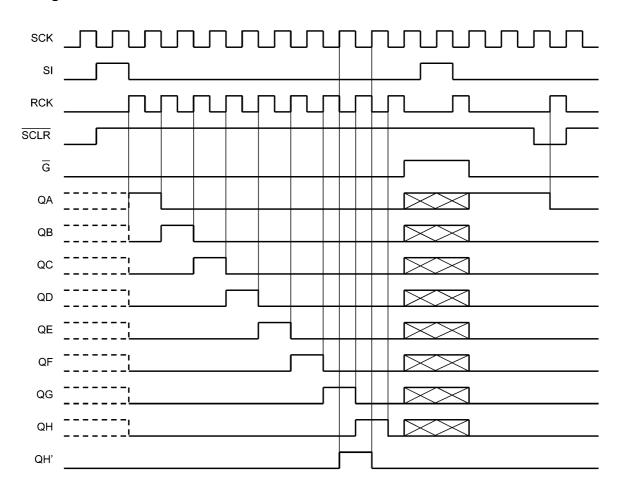
8. Truth Table

	Inputs			Function	
SI	SCK	SCLR	RCK	Ġ	Fullction
Х	Х	X	X	Ι	QA thru QH outputs disable
Х	Х	Х	Х	L	QA thru QH outputs enable
Х	Х	LI.	X	X	Shift register is cleared.
L		Н	Х	Х	First stage of S.R. becomes "L". Other stages store the data of previous stage, respectively.
Н		Н	Х	Х	First stage of S.R. becomes "H". Other stages store the data of previous stage, respectively.
Х	T	Н	Х	Х	State of S.R. is not changed.
Х	Х	Х		Х	S.R. data is stored into storage register.
Х	Х	Х		Х	Storage register stage is not changed.

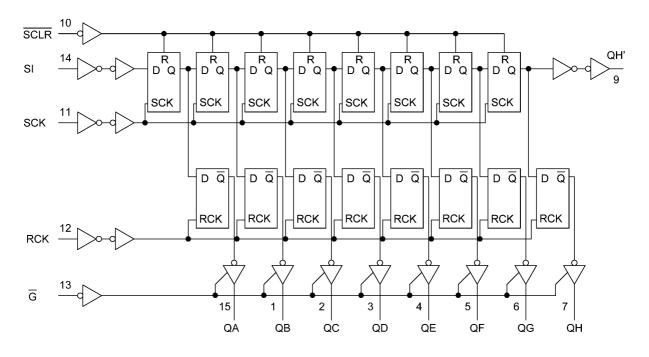
X: Don't care



9. Timing Chart



10. System Diagram





11. Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V _{CC}		-0.5 to 7.0	V
Input voltage	V _{IN}		-0.5 to 7.0	V
Output voltage	V _{OUT}		-0.5 to V _{CC} + 0.5	V
Input diode current	I _{IK}		-20	mA
Output diode current	I _{OK}		±20	mA
Output current	I _{OUT}		±25	mA
V _{CC} /ground current	I _{CC}		±75	mA
Power dissipation	P _D	(Note 1)	180	mW
Storage temperature	T _{stg}		-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: 180 mW in the range of T_a = -40 to 85 °C. From T_a = 85 to 125 °C a derating factor of -3.25 mW/°C shall be applied until 50 mW.

12. Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	V _{CC}		2.0 to 5.5	V
Input voltage	V _{IN}		0 to 5.5	V
Output voltage	V _{OUT}		0 to V _{CC}	V
Operating temperature	T _{opr}		-40 to 125	°C
Input rise and fall times	dt/dv	$V_{CC} = 3.3 \pm 0.3 \text{ V}$	0 to 100	ns/V
		V_{CC} = 5.0 ± 0.5 V	0 to 20	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either V_{CC} or GND.



13. Electrical Characteristics

13.1. DC Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition		V _{CC} (V)	Min	Тур.	Max	Unit
High-level input voltage	V _{IH}	_		2.0	1.50	_	_	V
				3.0 to 5.5	V _{CC} × 0.7	_	_	
Low-level input voltage	V _{IL}	_		2.0	_	_	0.50	V
				3.0 to 5.5	_	_	V _{CC} × 0.3	
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -50 μA	2.0	1.9	2.0	_	V
				3.0	2.9	3.0	_	
				4.5	4.4	4.5	_	
			I _{OH} = -4 mA	3.0	2.58	_	_	
			I _{OH} = -8 mA	4.5	3.94	_	_	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 50 μA	2.0	_	0.0	0.1	V
				3.0	_	0.0	0.1	
				4.5		0.0	0.1	
			I _{OL} = 4 mA	3.0	_	_	0.36	
			I _{OL} = 8 mA	4.5	_	_	0.36	
3-state output OFF-state leakage current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	_	±0.25	μА
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5			±0.1	μΑ
Quiescent supply current	Icc	V _{IN} = V _{CC} or GND		5.5	_	_	4.0	μΑ

13.2. DC Characteristics (Unless otherwise specified, T_a = -40 to 85 °C)

Characteristics	Symbol	Test Condition		V _{CC} (V)	Min	Max	Unit
High-level input voltage	V _{IH}	_		2.0	1.50	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	V _{IL}	_		2.0	_	0.50	V
				3.0 to 5.5	_	$V_{CC} \times 0.3$	
High-level output voltage	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OH} = -50 μA	2.0	1.9	_	V
				3.0	2.9	_	
				4.5	4.4	_	
			I _{OH} = -4 mA	3.0	2.48	_	
			I _{OH} = -8 mA	4.5	3.80	_	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 50 μA	2.0	_	0.1	V
				3.0	_	0.1	
				4.5	_	0.1	
			I _{OL} = 4 mA	3.0	_	0.44	
			I _{OL} = 8 mA	4.5	_	0.44	
3-state output OFF-state leakage current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	±2.50	μА
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_	±1.0	μΑ
Quiescent supply current	I _{CC}	$V_{IN} = V_{CC}$ or GND		5.5		40.0	μΑ



13.3. DC Characteristics (Unless otherwise specified, T_a = -40 to 125 °C)

Characteristics	Symbol	Test Condition	on	V _{CC} (V)	Min	Max	Unit
High-level input voltage	V _{IH}	_		2.0	1.50	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	V _{IL}	_		2.0	_	0.50	V
				3.0 to 5.5		$V_{CC} \times 0.3$	
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -50 μA	2.0	1.9	_	V
				3.0	2.9	_	
				4.5	4.4	_	
			$I_{OH} = -4 \text{ mA}$	3.0	2.40	_	
			I_{OH} = -8 mA	4.5	3.70	_	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 50 μA	2.0	_	0.1	V
				3.0	_	0.1	
				4.5	_	0.1	
			I _{OL} = 4 mA	3.0	_	0.55	
			I_{OL} = 8 mA	4.5	_	0.55	
3-state output OFF-state leakage current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	±10.0	μА
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5		±2.0	μΑ
Quiescent supply current	Icc	V _{IN} = V _{CC} or GND		5.5	_	80.0	μΑ

13.4. Timing Requirements (Unless otherwise specified, $T_a = 25$ °C, Input: $t_f = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Limit	Unit
Minimum pulse width (SCK, RCK)	$t_{w(L)}, t_{w(H)}$	_	3.3 ± 0.3	5.0	ns
			5.0 ± 0.5	5.0	
Minimum pulse width (SCLR)	t _{w(L)}	_	3.3 ± 0.3	5.0	
			5.0 ± 0.5	5.0	
Minimum setup time (SI-SCK)	t _S	_	3.3 ± 0.3	3.5	ns
			5.0 ± 0.5	3.0	
Minimum setup time (SCK - RCK)	t _S	_	3.3 ± 0.3	8.0	
			5.0 ± 0.5	5.0	
Minimum setup time (SCLR -RCK)	t _S	_	3.3 ± 0.3	8.0	
			5.0 ± 0.5	5.0	
Minimum hold time (SI-SCK)	t _h	_	3.3 ± 0.3	1.5	ns
			5.0 ± 0.5	2.0	
Minimum hold time (SCK-RCK)	t _h	_	3.3 ± 0.3	0	
			5.0 ± 0.5	0	
Minimum hold time (SCLR-RCK)	t _h	_	3.3 ± 0.3	0	
			5.0 ± 0.5	0	
Minimum removal time (SCLR)	t _{rem}	_	3.3 ± 0.3	3.0	ns
			5.0 ± 0.5	2.5	



13.5. Timing Requirements (Unless otherwise specified, $T_a = -40$ to 85°C, Input: $t_f = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Limit	Unit
Minimum pulse width (SCK, RCK)	$t_{w(L)}, t_{w(H)}$	_	3.3 ± 0.3	5.0	ns
			5.0 ± 0.5	5.0	
Minimum pulse width (SCLR)	t _{w(L)}	_	3.3 ± 0.3	5.0	
			5.0 ± 0.5	5.0	
Minimum setup time (SI-SCK)	t _S	_	3.3 ± 0.3	3.5	ns
			5.0 ± 0.5	3.0	
Minimum setup time (SCK - RCK)	t _S	_	3.3 ± 0.3	8.5	
			5.0 ± 0.5	5.0	
Minimum setup time (SCLR -RCK)	t _S	_	3.3 ± 0.3	9.0	
			5.0 ± 0.5	5.0	
Minimum hold time (SI-SCK)	t _h	_	3.3 ± 0.3	1.5	ns
			5.0 ± 0.5	2.0	
Minimum hold time (SCK-RCK)	t _h	_	3.3 ± 0.3	0	
			5.0 ± 0.5	0	
Minimum hold time (SCLR-RCK)	t _h	_	3.3 ± 0.3	0	
			5.0 ± 0.5	0	
Minimum removal time (SCLR)	t _{rem}	_	3.3 ± 0.3	3.0	ns
			5.0 ± 0.5	2.5	

13.6. Timing Requirements (Unless otherwise specified, T_a = -40 to 125 °C, Input: t_f = t_f = 3 ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Limit	Unit
Minimum pulse width (SCK, RCK)	$t_{w(L)}, t_{w(H)}$	_	3.3 ± 0.3	5.0	ns
			5.0 ± 0.5	5.0	
Minimum pulse width (SCLR)	t _{w(L)}	_	3.3 ± 0.3	5.0	
			5.0 ± 0.5	5.0	
Minimum setup time (SI-SCK)	t _S	_	3.3 ± 0.3	4.5	ns
			5.0 ± 0.5	3.5	
Minimum setup time (SCK - RCK)	t _S	_	3.3 ± 0.3	9.0	
			5.0 ± 0.5	5.0	
Minimum setup time (SCLR -RCK)	t _S	_	3.3 ± 0.3	10.0	
			5.0 ± 0.5	5.5	
Minimum hold time (SI-SCK)	t _h	_	3.3 ± 0.3	1.5	ns
			5.0 ± 0.5	2.0	
Minimum hold time (SCK-RCK)	t _h	_	3.3 ± 0.3	0	
			5.0 ± 0.5	0	
Minimum hold time (SCLR -RCK)	t _h	_	3.3 ± 0.3	0	
			5.0 ± 0.5	0	
Minimum removal time (SCLR)	t _{rem}	_	3.3 ± 0.3	4.0	ns
			5.0 ± 0.5	3.0	



13.7. AC Characteristics (Unless otherwise specified, T_a = 25 °C, Input: t_r = t_f = 3 ns)

Characteristics	Symbol	Note	Test Condition	V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}		_	3.3 ± 0.3	15	_	8.8	13.0	ns
(SCK-QH')					50		11.3	16.5	
				5.0 ± 0.5	15	_	6.2	8.2	
					50	_	7.7	10.2	
Propagation delay time	t _{PHL}		_	3.3 ± 0.3	15	_	8.4	12.8	ns
(SCLR -QH')					50		10.9	16.3	
				5.0 ± 0.5	15	_	5.9	8.0	
					50	_	7.4	10.0	
Propagation delay time	t _{PLH} ,t _{PHL}		_	3.3 ± 0.3	15	1	7.7	11.9	ns
(RCK-Q _n)					50	_	10.2	15.4	
				5.0 ± 0.5	15	_	5.4	7.4	
					50	_	6.9	9.4	
3-state output enable time	t _{PZL} ,t _{PZH}		$R_L = 1 k\Omega$	3.3 ± 0.3	15	_	7.5	11.5	ns
					50	_	9.0	15.0	
				5.0 ± 0.5	15	_	4.8	8.6	
					50	_	8.3	10.6	
3-state output disable time	t_{PLZ}, t_{PHZ}		$R_L = 1 k\Omega$	3.3 ± 0.3	50	_	12.1	15.7	ns
				5.0 ± 0.5	50		7.6	10.3	
Maximum clock frequency	f _{MAX}		_	3.3 ± 0.3	15	80	150	_	MHz
					50	55	130	_	
				5.0 ± 0.5	15	135	185	_	
					50	95	155	_	
Input capacitance	C _{IN}		_	•	•	_	4	10	pF
Output capacitance	C _{OUT}		_			_	6	_	
Power dissipation capacitance	C _{PD}	(Note 1)	_			_	87	_	

Note 1: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

$$I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}$$



13.8. AC Characteristics (Unless otherwise specified, T_a = -40 to 85 °C, Input: t_f = t_f = 3 ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	C _L (pF)	Min	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}	_	3.3 ± 0.3	15	1.0	15.0	ns
(SCK-QH')				50	1.0	18.5	
			5.0 ± 0.5	15	1.0	9.4]
				50	1.0	11.4	
Propagation delay time	t _{PHL}	_	3.3 ± 0.3	15	1.0	13.7	ns
(SCLR -QH')				50	1.0	17.2]
			5.0 ± 0.5	15	1.0	9.1	
				50	1.0	11.1	
Propagation delay time	t _{PLH} ,t _{PHL}	_	3.3 ± 0.3	15	1.0	13.5	ns
(RCK-Q _n)				50	1.0	17.0]
			5.0 ± 0.5	15	1.0	8.5	
				50	1.0	10.5	
3-state output enable time	t_{PZL}, t_{PZH}	$R_L = 1 k\Omega$	3.3 ± 0.3	15	1.0	13.5	ns
				50	1.0	17.0	
			5.0 ± 0.5	15	1.0	10.0]
				50	1.0	12.0]
3-state output disable time	t _{PLZ} ,t _{PHZ}	$R_L = 1 k\Omega$	3.3 ± 0.3	50	1.0	16.2	ns
			5.0 ± 0.5	50	1.0	11.0]
Maximum clock frequency	f _{MAX}	_	3.3 ± 0.3	15	70	_	MHz
				50	50	_]
			5.0 ± 0.5	15	115	_]
				50	85	_	1
Input capacitance	C _{IN}					10	pF



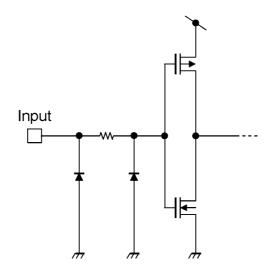
13.9. AC Characteristics (Unless otherwise specified, T_a = -40 to 125 °C, Input: t_r = t_f = 3 ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	C _L (pF)	Min	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}	_	3.3 ± 0.3	15	1.0	17.5	ns
(SCK-QH')				50	1.0	21.0	
			5.0 ± 0.5	15	1.0	11.0]
				50	1.0	13.0	
Propagation delay time	t _{PHL}	_	3.3 ± 0.3	15	1.0	17.0	ns
(SCLR -QH')				50	1.0	20.5	
			5.0 ± 0.5	15	1.0	10.5	
				50	1.0	12.5	
Propagation delay time	t _{PLH} ,t _{PHL}	_	3.3 ± 0.3	15	1.0	16.0	ns
(RCK-Q _n)				50	1.0	19.5	
			5.0 ± 0.5	15	1.0	10.0	
				50	1.0	12.0	
3-state output enable time	t _{PZL} ,t _{PZH}	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	15	1.0	15.5	ns
				50	1.0	19.0	
			5.0 ± 0.5	15	1.0	11.5	
				50	1.0	13.5	
3-state output disable time	t _{PLZ} ,t _{PHZ}	$R_L = 1 \text{ k}\Omega$	3.3 ± 0.3	50	1.0	20.0	ns
			5.0 ± 0.5	50	1.0	13.0]
Maximum clock frequency	f _{MAX}	_	3.3 ± 0.3	15	60	_	MHz
				50	40	_	
			5.0 ± 0.5	15	105	_	
				50	75	_	
Input capacitance	C _{IN}				_	10	pF

13.10. Noise Characteristics (Unless otherwise specified, $T_a = 25$ °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	C _L = 50 pF	5.0	0.8	1.0	V
Quiet output minimum dynamic V _{OL}	V _{OLV}	C _L = 50 pF	5.0	-0.8	-1.0	
Minimum high-level dynamic input voltage	V_{IHD}	C _L = 50 pF	5.0	1	3.5	
Maximum low-level dynamic input voltage	V_{ILD}	C _L = 50 pF	5.0		1.5	

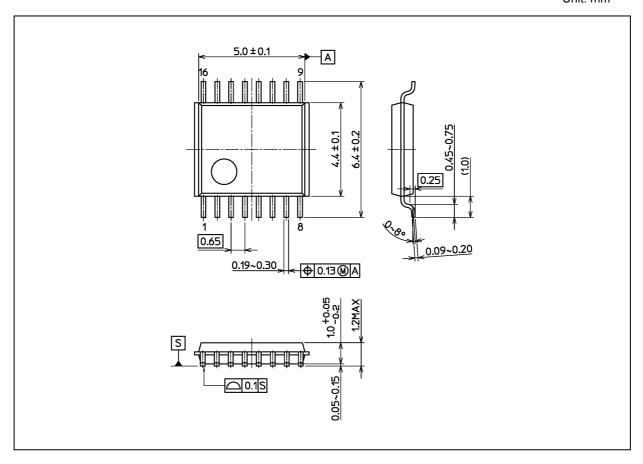
14. Input Equivalent Circuit





Package Dimensions

Unit: mm



Weight: 0.055 g (typ.)

	Package Name(s)
Nickname: TSSOP16B	



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